Receipt date: 07/10/2008	10551735 - GAU: 287 Page 1 of 5		
Form PTO-1449 U.S. Department of Commerce (REV. 2-82) Patent and Trademark Office	Atty. Docket No. 36217/US/2-475387-191	Serial No. 10/551,735	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT	Applicant(s) Guillermo J. Tearney et al.		
(Use several sheets if necessary)	Filing Date	Confirmation No.	

Spetember 29, 2005

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		6	7	4	1	3	5	5	May 25, 2004	Drabarek EEEEEEEE			
	2005	0	0	7	5	5	4	7	April 7, 2005	Wang €€€€€€€€			
_	2005	0	0	8	3	5	3	4	April 21, 2005	Riza et al. EEEEEEEE			
		3	9	7	3	2	1	9	August 3, 1976	Tang et al.			
		3	9	8	3	5	0	7	September 28, 1976	Tang et al.			
	2006	0	1	0	3	8	5	0	May 18, 2006	Alphonse et al.			
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·		6	4	5	9	4	8	7	October 1, 2002	Chen et al.ф			
	2002	0	0	9	3	6	6	2	July 18, 2002	Chen et al. ф			
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		6	9	0	3	8	2	0	June 7, 2005	Wang фффф			
	2006	0	2	4	4	9	7	3	November 2, 2006	Yun et al. ффффф			
		5	2	2	8	0	0	1	July 13, 1993	Birge et al. фффффф			
		6	6	8	7	0	3	6	February 3, 2004	Riza фффффф			
		4	4	2	8	6	4	3	January 31, 1984	Кау фффффф			
	-	4	9	6	5	5	9	9	October 23, 1990	Roddy et al. фффффф			

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^{*} Examiner: Initial citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered recommendation of the conformation of t

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